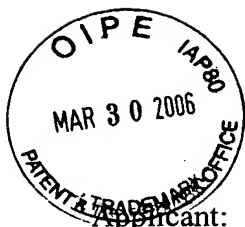


PATENT



IN THE UNITED STATES PATENT
AND TRADEMARK OFFICE

Applicant: Geun Su Lee et al.

Serial No.: 10/723,029

Filed: November 26, 2003

Title: Cleaning Solution for Photoresist and Method for Forming Pattern Using the Same

Group Art Unit: 1756

Examiner: Not yet assigned

I hereby certify that this paper (or fee) is being deposited with the United States Postal Service, first class postage prepaid, addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450

March 28, 2006

James P. Zeller
Reg. No. 28,491

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

The documents listed on the enclosed Form PTO-1449 are identified pursuant to 37 CFR §§ 1.56, 1.97, and 1.98. Copies of the documents are enclosed as required.

The documents were cited in an official action (copy submitted herewith) dated December 28, 2005, during the prosecution of counterpart Korean Patent Application No. 2003-14796.

Entry and consideration of the submitted documents are solicited.

Respectfully submitted,

MARSHALL, GERSTEIN & BORUN LLP

March 28, 2006

By: 

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USPTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Atty. Docket No.	Serial No.
		30205/39714	10/723,029
		Applicant	
		Geun Su Lee	
		Filing Date	Group
		11/26/2003	1756

INFORMATION DISCLOSURE STATEMENT**U.S. PATENT DOCUMENTS**

*Examiner Initials	Document Number	Issue Date	Name	Class	Subclass	Filing Date if Appropriate
	3,953,386	04/27/76	Murphy et al	260	17	
	5,196,070	03/23/93	Ables et al	148	23	

FOREIGN PATENT DOCUMENTS

*Examiner Initials	Document Number	Publication Date	Country	Class	Subclass	Translation	
						Yes	No
	04-124668	04/24/92	Japan			Abstract only	

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

	Office action in corresponding Korean Application No. 2003-14796 dated December 28, 2005

Examiner	Date Considered
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	